
AIS2DW12: ultralow-power 3-axis accelerometer for automotive applications

Introduction

This document provides usage information and application hints related to ST's AIS2DW12 motion sensor.

The AIS2DW12 is an ultralow-power three-axis linear accelerometer designed to address nonsafety automotive applications and which leverages on the robust and mature manufacturing processes already used for the production of micromachined accelerometers.

The device has four different ultralow-power modes, two user-selectable full scales ($\pm 2g/\pm 4g$) and is capable of measuring accelerations with output data rates from 1.6 Hz to 100 Hz.

The AIS2DW12 has an integrated 32-level first-in, first-out (FIFO) buffer allowing the user to store data in order to limit intervention by the host processor. The device includes a dedicated internal engine to process motion and acceleration detection including free-fall, motion and no-motion, wake-up, activity/inactivity and 6D/4D orientation.

The embedded self-test capability allows the user to check the functioning of the sensor in the final application.

The AIS2DW12 is available in a small thin plastic, land grid array (LGA) package and it is guaranteed to operate over an extended temperature range from -40°C to $+85^{\circ}\text{C}$.

1 Pin description

Figure 1. Pin connections

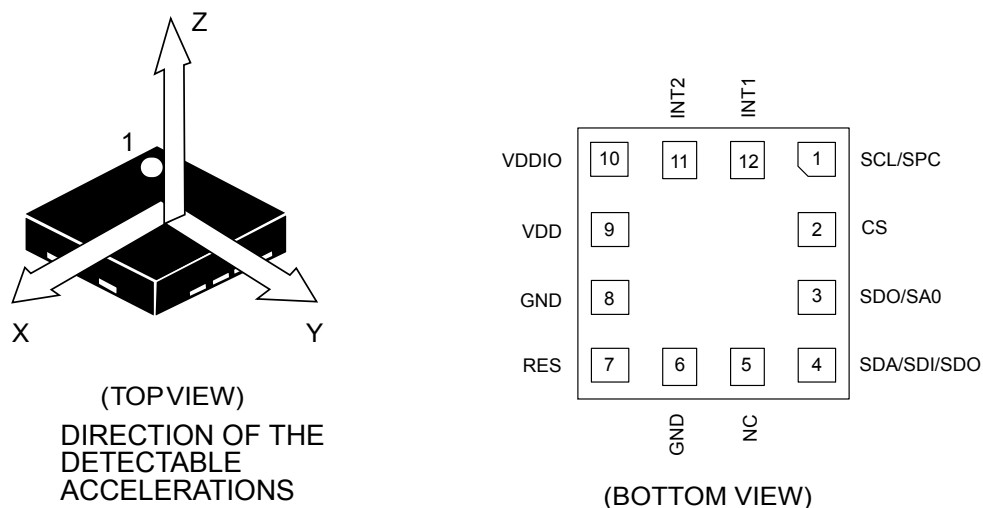


Table 1. Pin description

Pin#	Name	Function	Pin status
1	SCL SPC	I ² C serial clock (SCL) SPI serial port clock (SPC)	Default: input without internal pull-up
2	CS	SPI enable I ² C/SPI mode selection (1: SPI idle mode / I ² C communication enabled; 0: SPI communication mode / I ² C disabled)	Default: input with internal pull-up ⁽¹⁾
3	SDO SA0	SPI serial data output (SDO) I ² C less significant bit of the device address (SA0)	Default: input with internal pull-up ⁽²⁾
4	SDA SDI SDO	I ² C serial data (SDA) SPI serial data input (SDI) 3-wire interface serial data output (SDO)	Default: (SDA) input without internal pull-up
5	NC	Internally not connected. Can be tied to VDD, VDDIO, or GND.	
6	GND	0 V supply	
7	RES	Connect to GND	
8	GND	0 V supply	
9	VDD	Power supply	
10	VDDIO	Power supply for I/O pins	
11	INT2	Interrupt pin 2. Clock input when selected in single data conversion on demand.	Default: push-pull output forced to ground
12	INT1	Interrupt pin 1	Default: push-pull output forced to ground

1. In order to disable the internal pull-up on the CS pin, write the CS_PU_DISC bit to 1 in CTRL2 (21h).

2. Internal pull-up on SDO/SA0 pin cannot be disabled. Do not connect this pin to GND in low-power applications.

2 Registers

Table 2. Registers

Register name	Address	Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
OUT_T_L	0Dh	TEMP3	TEMP2	TEMP1	TEMP0	0	0	0	0
OUT_T_H ⁽¹⁾	0Eh	TEMP11	TEMP10	TEMP9	TEMP8	TEMP7	TEMP6	TEMP5	TEMP4
WHO_AM_I ⁽¹⁾	0Fh	0	1	0	0	0	1	0	0
CTRL1	20h	ODR3	ODR2	ODR1	ODR0	OP_MODE1	OP_MODE0	PW_MODE1	PW_MODE0
CTRL2	21h	BOOT	SOFT_RESET	0	CS_PU_DISC	BDU	IF_ADD_INC	I2C_DISABLE	SIM
CTRL3	22h	ST2	ST1	PP_OD	LIR	H_LACTIVE	0	SLP_MODE_SEL	SLP_MODE_1
CTRL4_INT1	23h	INT1_6D	0	INT1_WU	INT1_FF	0	INT1_DIFF5	INT1_FTH	INT1_DRDY
CTRL5_INT2	24h	INT2_SLEEP_STATE	INT2_SLEEP_CHG	INT2_BOOT	INT2_DRDY_T	INT2_OVR	INT2_DIFF5	INT2_FTH	INT2_DRDY
CTRL6	25h	BW_FILT1	BW_FILT0	FS1	FS0	FDS	0	0	0
OUT_T ⁽¹⁾	26h	TEMP7	TEMP6	TEMP5	TEMP4	TEMP3	TEMP2	TEMP1	TEMP0
STATUS ⁽¹⁾	27h	FIFO_THS	WU_IA	SLEEP_STATE	0	0	6D_IA	FF_IA	DRDY
OUT_X_L ⁽¹⁾	28h	X_L7	X_L6	X_L5	X_L4	X_L3 ⁽²⁾	X_L2 ⁽²⁾	0	0
OUT_X_H ⁽¹⁾	29h	X_H7	X_H6	X_H5	X_H4	X_H3	X_H2	X_H1	X_H0
OUT_Y_L ⁽¹⁾	2Ah	Y_L7	Y_L6	Y_L5	Y_L4	Y_L3 ⁽²⁾	Y_L2 ⁽²⁾	0	0
OUT_Y_H ⁽¹⁾	2Bh	Y_H7	Y_H6	Y_H5	Y_H4	Y_H3	Y_H2	Y_H1	Y_H0
OUT_Z_L ⁽¹⁾	2Ch	Z_L7	Z_L6	Z_L5	Z_L4	Z_L3 ⁽²⁾	Z_L2 ⁽²⁾	0	0
OUT_Z_H ⁽¹⁾	2Dh	Z_H7	Z_H6	Z_H5	Z_H4	Z_H3	Z_H2	Z_H1	Z_H0
FIFO_CTRL	2Eh	FMode2	FMode1	FMode0	FTH4	FTH3	FTH2	FTH1	FTH0
FIFO_SAMPLES ⁽¹⁾	2Fh	FIFO_FTH	FIFO_OVR	Diff5	Diff4	Diff3	Diff2	Diff1	Diff0
SIXD_THS	30h	4D_EN	6D_THS1	6D_THS0	0	0	0	0	0
WAKE_UP_THS	34h	0	SLEEP_ON	WK_THS5	WK_THS4	WK_THS3	WK_THS 2	WK_THS 1	WK_THS 0
WAKE_UP_DUR	35h	FF_DUR5	WAKE_DUR1	WAKE_DUR0	STATIONARY	SLEEP_DUR3	SLEEP_DUR2	SLEEP_DUR1	SLEEP_DUR0
FREE_FALL	36h	FF_DUR4	FF_DUR3	FF_DUR2	FF_DUR1	FF_DUR0	FF_THS2	FF_THS1	FF_THS0
STATUS_DUP ⁽¹⁾	37h	OVR	DRDY_T	SLEEP_STATE_IA	0	0	6D_IA	FF_IA	DRDY
WAKE_UP_SRC ⁽¹⁾	38h	0	0	FF_IA	SLEEP_STATE IA	WU_IA	X_WU	Y_WU	Z_WU
SIXD_SRC ⁽¹⁾	3Ah	0	6D_IA	ZH	ZL	YH	YL	XH	XL
ALL_INT_SRC ⁽¹⁾	3Bh	0	0	SLEEP_	6D_IA	0	0	WU_IA	FF_IA





Register name	Address	Bit7	Bit6	Bit5	Bit4	Bit3	Bit2	Bit1	Bit0
				CHANGE_IA					
X_OFS_USR	3Ch	X_OFS_USR_7	X_OFS_USR_6	X_OFS_USR_5	X_OFS_USR_4	X_OFS_USR_3	X_OFS_USR_2	X_OFS_USR_1	X_OFS_USR_0
Y_OFS_USR	3Dh	Y_OFS_USR_7	Y_OFS_USR_6	Y_OFS_USR_5	Y_OFS_USR_4	Y_OFS_USR_3	Y_OFS_USR_2	Y_OFS_USR_1	Y_OFS_USR_0
Z_OFS_USR	3Eh	Z_OFS_USR_7	Z_OFS_USR_6	Z_OFS_USR_5	Z_OFS_USR_4	Z_OFS_USR_3	Z_OFS_USR_2	Z_OFS_USR_1	Z_OFS_USR_0
CTRL7	3Fh	DRDY_ PULSED	INT2_ON_INT1	INTERRUPTS _ENABLE	USR_OFF_ON _OUT	USR_OFF_ON _WU	USR_OFF_W	HP_REF_ MODE	LPASS_ON6D

1. Read-only register
2. If low-power mode 1 is enabled, this bit is set to 0.

3 Operating modes

The device offers a wide VDD voltage range from 1.62 V to 3.6 V and a VDDIO range from 1.62 V to VDD + 0.1 V. In order to avoid potential conflicts, during the power-on sequence it is recommended to set the lines (on the host side) connected to the device IO pins floating or connected to ground, until VDDIO is set. After VDDIO is set, the lines connected to the IO pins have to be configured according to their default status described in Table 1. In order to avoid an unexpected increase in current consumption, the input pins that are not pulled-up/pulled-down must be polarized by the host.

When the VDD power supply is applied, the device performs a 20 ms (maximum) boot procedure to load the trimming parameters. After the boot is completed, both the accelerometer and the gyroscope are automatically configured in power-down mode. To guarantee proper power-off of the device, VDD needs to be lower than 100 mV for at least 10 ms.

Note: VDD cannot be lower than VDDIO. VDD = 0 V and VDDIO "on" is allowed: when this power supply configuration is applied, an internal pull-up is applied also to the SDA and SCL pins (the other pins maintain the default status indicated in Table 1).

3.1 Power mode

Four sets of operating modes have been designed to offer the customer a broad choice of noise/power-consumption combinations.

Table 3. Accelerometer resolution

Power mode 4	Power mode 3	Power mode 2	Power mode 1
14-bit	14-bit	14-bit	12-bit

These operating modes are selected by writing the OP_MODE[1:0] and PW_MODE[1:0] bits in CTRL1 (20h) given in the tables below. Additional details concerning power consumption and noise in different operating modes are available in the device datasheet.

Table 4. CTRL1 register

b7	b6	b5	b4	b3	b2	b1	b0
ODR3	ODR2	ODR1	ODR0	OP_MODE1	OP_MODE0	PW_MODE1	PW_MODE0

Table 5. Operating mode selection

OP_MODE[1:0]	Operating mode and resolution
00	Continuous mode (12/14-bit resolution)
01	Not allowed
10	Single data conversion on-demand mode (12/14-bit resolution)
11	Not allowed

Table 6. Power mode selection

PW_MODE[1:0]	Power mode and resolution
00	Power mode 1 (12-bit resolution)
01	Power mode 2 (14-bit resolution)
10	Power mode 3 (14-bit resolution)
11	Power mode 4 (14-bit resolution)

3.2 Continuous conversion

When bits OP_MODE[1:0] in CTRL1 (20h) are set to 00 (continuous mode), the device is in continuous conversion and the output data rate can be selected through the ODR[3:0] bits in CTRL1 (20h).

Table 7. Output data rate selection

ODR[3:0]	Output data rate
0000	Power-down
0001	1.6 Hz (independent of power mode)
0010	12.5 Hz (independent of power mode)
0011	25 Hz (independent of power mode)
0100	50 Hz (independent of power mode)
0101	100 Hz (independent of power mode)

3.3 Single data conversion (on-demand mode)

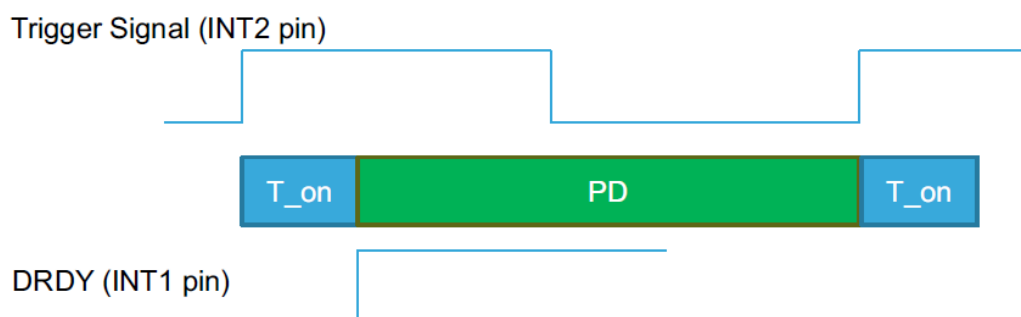
This mode is enabled by writing the OP_MODE[1:0] bits to 10 in CTRL1 (20h).

In this configuration, the device waits for a trigger signal in order to generate new data according to the selected power mode PW_MODE[1:0] bits in CTRL1 (20h), after that the device immediately enters power-down.

The trigger can be:

- **A rising edge on the INT2 pin (if SLP_MODE_SEL = 0 in register CTRL3 (22h)).** In this case, the user can detect the end of the conversion using the DRDY bit of the STATUS register (27h) that can also be routed to the INT1 pin by setting the INT1_DRDY bit to 1 in register CTRL4_INT1 (23h). The minimum duration of trigger signal high level is 20 ns.
- **A write of SLP_MODE_1 to 1 in register CTRL3 (22h) (if SLP_MODE_SEL = 1 in register CTRL3 (22h)).** In this case, the user can detect the end of the conversion using the DRDY bit/signal as in the previous case, or by checking when the SLP_MODE_1 bit in register CTRL3 (22h) is automatically cleared.

Figure 2. Single data conversion using INT2 as external trigger (SLP_MODE_SEL = 0)



The maximum data rate using single data conversion mode is 100 Hz and the time of conversion depends on the low-power mode selected (refer to the following table).

Table 8. Single data conversion: typical time of conversion

Power mode	Typical time of conversion (T _{on})
Mode 1	1.20 ms
Mode 2	1.70 ms
Mode 3	2.30 ms
Mode 4	3.55 ms

Note:

If the ODR[3:0] bits of the CTRL1 register are set to 0000, the accelerometer is permanently configured in power-down mode and no conversion can be triggered. When the single data conversion mode has to be used, the ODR[3:0] bits of the CTRL1 register must be different than 0000.

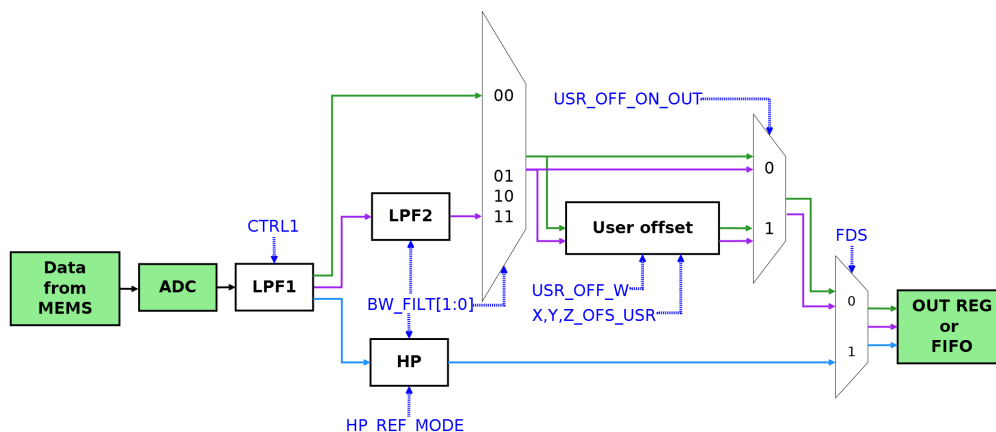
Interrupts, embedded features, and FIFO are still supported when using single data conversion mode. Also the embedded filters LPF1, LPF2, and HP are available in single data conversion (on-demand mode) with the same bandwidth and settling time of the selected low-power mode (see [Section 3.4 Accelerometer bandwidth](#) for details).

3.4 Accelerometer bandwidth

The accelerometer sampling chain (Figure 3. Accelerometer filtering chain diagram) is represented by a cascade of a few blocks:

- ADC: Analog-to-digital converter
- LPF1(2): low-pass filter 1(2)
- HP: high-pass filter
- User offset: configurable values that are subtracted from the sampled data (one for each axis)

Figure 3. Accelerometer filtering chain diagram



As shown in the figure above, data can be generated using three different filter paths:

- Only LPF1 (green path): in order to select this path set $BW_FILT[1:0] = 00$ and $FDS = 0$. Additional details in Table 9. Low-pass filter 1 bandwidth.
- LPF1 + LPF2 (purple path): in order to select this path set $BW_FILT[1:0]$ to a value different from 00 and $FDS = 0$. Additional details in Table 10. Bandwidth: low-pass path.
- LPF1 + HP (blue path): these outputs are available by setting $FDS = 1$. Additional details in Table 11. Bandwidth: high-pass path.

Table 9. Low-pass filter 1 bandwidth

Mode	ODR selection	BW_FILT[1:0] = 00	
		Samples to discard ⁽¹⁾ Settling @95%	Cutoff [Hz]
Power mode 4	@ each ODR	0	180
Power mode 3	@ each ODR	0	360
Power mode 2	@ each ODR	0	720
Power mode 1	@ each ODR	0	3200

1. The starting condition of $ODR[3:0]$, $OP_MODE[1:0]$, $PW_MODE[1:0]$, and $BW_FILT[1:0]$ does not impact these values. The turn-on time (the first sample available starting from the power-down condition) is $1 / ODR$.

Table 10. Bandwidth: low-pass path

Mode	ODR selection	BW_FILT[1:0] = 01		BW_FILT[1:0] = 10		BW_FILT[1:0] = 11	
		Samples to discard ⁽¹⁾ Settling @95%	Cutoff [Hz]	Samples to discard ⁽¹⁾ Settling @95%	Cutoff [Hz]	Samples to discard ⁽¹⁾ Settling @95%	Cutoff [Hz]
PW mode 4	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20
PW mode 3	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20
PW mode 2	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20
PW mode 1	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20

1. The starting condition of ODR[3:0], OP_MODE[1:0], PW_MODE[1:0], and BW_FILT[1:0] does not impact these values.

Table 11. Bandwidth: high-pass path

Mode	ODR selection	BW_FILT[1:0] = 01 / 00		BW_FILT[1:0] = 10		BW_FILT[1:0] = 11	
		Samples to discard ⁽¹⁾ Settling @95%	Cutoff [Hz]	Samples to discard ⁽¹⁾ Settling @95%	Cutoff [Hz]	Samples to discard ⁽¹⁾ Settling @95%	Cutoff [Hz]
PW mode 4	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20
PW mode 3	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20
PW mode 2	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20
PW mode 1	@ each ODR	1	ODR/4	5	ODR/10	11	ODR/20

1. The starting condition of ODR[3:0], OP_MODE[1:0], PW_MODE[1:0], and BW_FILT[1:0] does not impact these values.

Setting USR_OFF_ON_OUT = 1 in CTRL7 does not change the bandwidth of the system. In this configuration, the values written in registers X_OFS_USR, Y_OFS_USR, Z_OFS_USR are subtracted from the respective axis. The offset values are signed values (two's complement).

The weight of the bits in registers X_OFS_USR, Y_OFS_USR, Z_OFS_USR is defined through the USR_OFF_W bit in CTRL7.

3.5 High-pass filter configuration

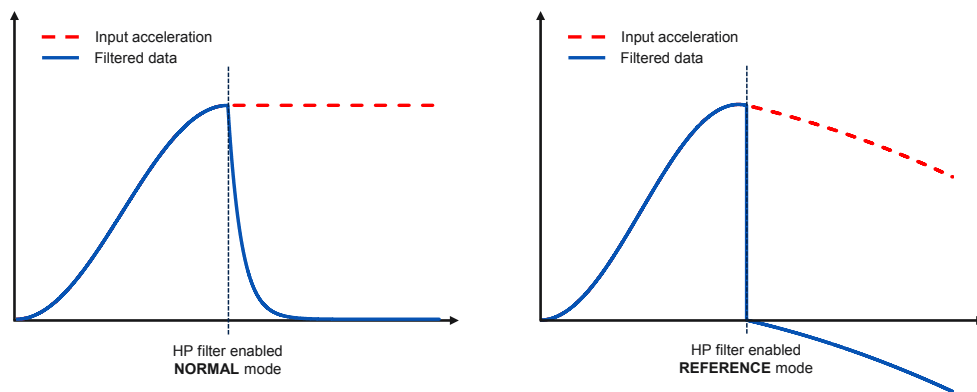
The AIS2DW12 provides an embedded high-pass filtering capability to easily delete the DC component of the measured acceleration. As shown in [Figure 3. Accelerometer filtering chain diagram](#), through the FDS bit in register CTRL6 the user can route the filter outputs to the output registers.

It is also possible to independently apply the filter to the embedded function data ([Figure 6. Embedded functions in Section 5 Interrupt generation and embedded functions](#)). This means that it is possible to get filtered data while the interrupt generation works on unfiltered data.

The high-pass filter can be configured in *reference mode* by setting the HP_REF_MODE bit in the CTRL7 register to 1. In this configuration, the output data is calculated as the difference between the measured acceleration and the output values captured when *reference mode* was enabled. In this way, only the difference is applied without any filtering.

As an example, this feature can be combined with the wake-up functionality described in [Section 5.4](#) in order to detect when the device is displaced with respect to a specific orientation, that is, the orientation of the device when the HP_REF_MODE bit was set to 1. When the output acceleration exceeds the wake-up threshold defined by the WK_THS[5:0] bits in the WAKE_UP_THS register for a duration longer than the one defined by the WAKE_DUR[1:0] bits in the WAKE_UP_DUR register, an interrupt is generated. If the device is moved back to the original reference orientation, the interrupt is deactivated.

Figure 4. High-pass filter in normal and reference mode



4 Reading output data

4.1 Startup sequence

Once the device is powered up, it automatically downloads the calibration coefficients from the embedded nonvolatile memory to the internal registers. When the boot procedure is completed, that is, after approximately 20 milliseconds, the accelerometer automatically enters power-down.

To turn on the accelerometer and gather acceleration data, it is necessary to select one of the operating modes through the CTRL1 register.

Refer to [Section 3 Operating modes](#) for a detailed description of data generation.

4.2 Using the status register

The device is provided with a STATUS register, which can be polled to check when a new set of data is available. The DRDY bit is set to 1 when a new set of data is available from the accelerometer output.

The read operations should be performed as follows:

1. Read the STATUS register.
2. If DRDY = 0, then go to 1.
3. Read OUT_X_L.
4. Read OUT_X_H.
5. Read OUT_Y_L.
6. Read OUT_Y_H.
7. Read OUT_Z_L.
8. Read OUT_Z_H.
9. Data processing
10. Go to 1.

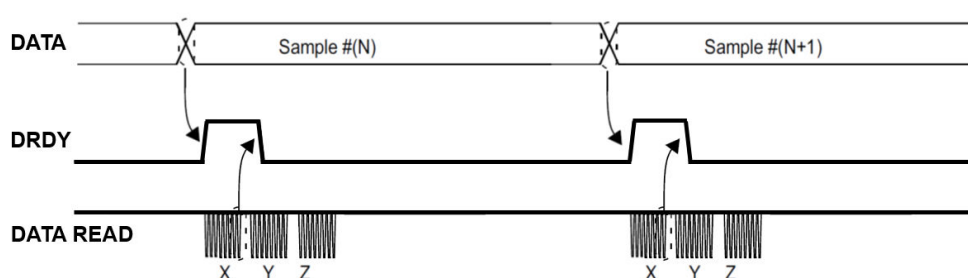
4.3 Using the data-ready signal

The device can be configured to have a hardware signal to determine when a new set of measurement data is available to be read.

The data-ready signal is derived from the DRDY bit of the STATUS register. The signal can be driven to the INT1 pin by setting the INT1_DRDY bit of the CTRL4_INT1 register to 1 and to the INT2 pin by setting the INT2_DRDY bit of the CTRL5_INT2 register to 1.

The data-ready signal rises to 1 when a new set of data has been measured and is available to be read. In DRDY latched mode (DRDY_PULSED bit = 0 in the CTRL7 register), which is the default condition, the signal gets reset when the higher byte of one axis has been read (29h, 2Bh, 2Dh). In DRDY pulsed mode (DRDY_PULSED = 1), the pulse duration can vary between 105 μ s and 175 μ s. Pulsed mode is not applied to the DRDY bit, which is always latched.

Figure 5. Data-ready signal



4.4 Using the block data update (BDU) feature

If reading the accelerometer data is not synchronized with either the DRDY event bit in the STATUS register or with the DRDY signal driven to the INT1/INT2 pins, it is strongly recommended to set the BDU (block data update) bit to 1 in the CTRL2 (21h) register.

This feature avoids reading values (most significant and least significant parts of output data) related to different samples. In particular, when the BDU is activated, the data registers related to each axis always contain the most recent output data produced by the device, but, in case the read of a given pair (that is, OUT_X_H and OUT_X_L, OUT_Y_H and OUT_Y_L, OUT_Z_H and OUT_Z_L) is initiated, the refresh for that pair is blocked until both the MSB and LSB of the data are read.

Note: BDU only guarantees that the LSB and MSB have been sampled at the same moment. For example, if the reading speed is too slow, X and Y can be read at T1 and Z sampled at T2.

4.5 Understanding output data

The measured acceleration data are sent to the OUT_X_H, OUT_X_L, OUT_Y_H, OUT_Y_L, OUT_Z_H, and OUT_Z_L registers. These registers contain, respectively, the most significant part and the least significant part of the acceleration signals acting on the X, Y, and Z axes.

The complete output data for the X, Y, Z channels is given by the concatenation OUT_X_H & OUT_X_L, OUT_Y_H & OUT_Y_L, OUT_Z_H & OUT_Z_L.

Acceleration data is represented as 16-bit numbers, left-aligned and encoded in two's complement. These values (LSB) have different resolution according to the selected operating mode.

After calculating the LSB, it must be multiplied by the proper sensitivity parameter to obtain the corresponding value in mg.

Table 12. Sensitivity

Full Scale	Sensitivity [mg/LSB]	
	12-bit format	14-bit format
±2 g	0.976	0.244
±4 g	1.952	0.488

4.5.1 Example of output data

Below is a simple example of how to use the LSB data and transform it into mg.

The values are given under the hypothesis of ideal device calibration (that is, no offset, no gain error, and so forth).

Get raw data from the sensor in 14-bit power mode at ±2 g:

OUT_X_L: 60h

OUT_X_H: FDh

OUT_Y_L: 78h

OUT_Y_H: 00h

OUT_Z_L: FCh

OUT_Z_H: 42h

Do register concatenation:

OUT_X_H & OUT_X_L: FD60h

OUT_Y_H & OUT_Y_L: 0078h

OUT_Z_H & OUT_Z_L: 42FCh

Apply sensitivity (for example, 14-bit resolution, 0.244 at full scale ±2 g):

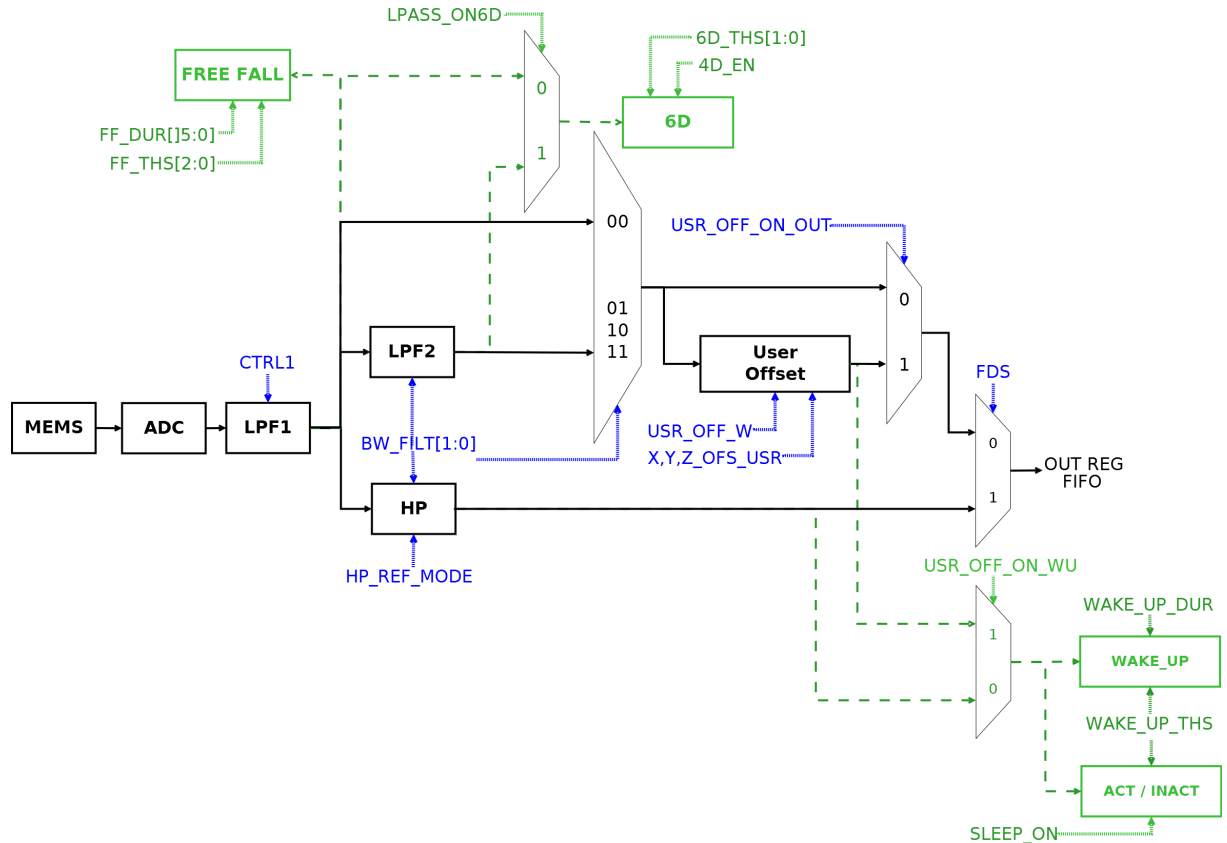
X: $-672 / 4 * 0.244 = -41 \text{ mg}$

Y: $+120 / 4 * 0.244 = +7 \text{ mg}$

Z: $+17148 / 4 * 0.244 = +1046 \text{ mg}$

5 Interrupt generation and embedded functions

Figure 6. Embedded functions



In order to generate an interrupt, the AIS2DW12 device has to be set in an active operating mode (not in power-down) because generation of the interrupt is based on accelerometer data.

The interrupt generator can be configured to detect:

- Free-fall
- Wake-up
- 6D/4D orientation detection
- Activity/inactivity detection

All these interrupt signals, together with the FIFO interrupt signals and sensor data-ready, can be driven to the INT1 and/or INT2 interrupt pins or checked by reading the dedicated source register bits.

The H_LACTIVE bit of the CTRL3 register must be used to select the polarity of the interrupt pins. If this bit is set to 0 (default value), the interrupt pins are active high and they change from low to high level when the related interrupt condition is verified. Otherwise, if the H_LACTIVE bit is set to 1 (active low), the interrupt pins are normally at high level and they change from high to low when the interrupt condition is reached.

The PP_OD bit of CTRL3 allows changing the behavior of the interrupt pins also when the DRDY signal is routed to them from push-pull to open drain. If the PP_OD bit is set to 0, the interrupt pins are in push-pull configuration (low-impedance output for both high and low level). When the PP_OD bit is set to 1, only the interrupt active state is a low-impedance output.

The LIR bit of CTRL3 allows applying latched mode to the interrupt signals (not affecting the DRDY signal). When the LIR bit is set to 1, once the interrupt pin is asserted, it must be reset by reading the related interrupt source register. If the LIR bit is set to 0, the interrupt signal is automatically reset when the interrupt condition is no longer verified or after a certain amount of time in function of the type of interrupt.

Note: *If latched mode is enabled (LIR = 1), it is not recommended to continuously poll the ALL_INT_SRC or the dedicated source registers because by reading them the embedded functions are internally reset; a synchronous (with interrupt event) read of the source registers is recommended in this case.*

5.1 Interrupt pin configuration

The device is provided with two pins that can be activated to generate:

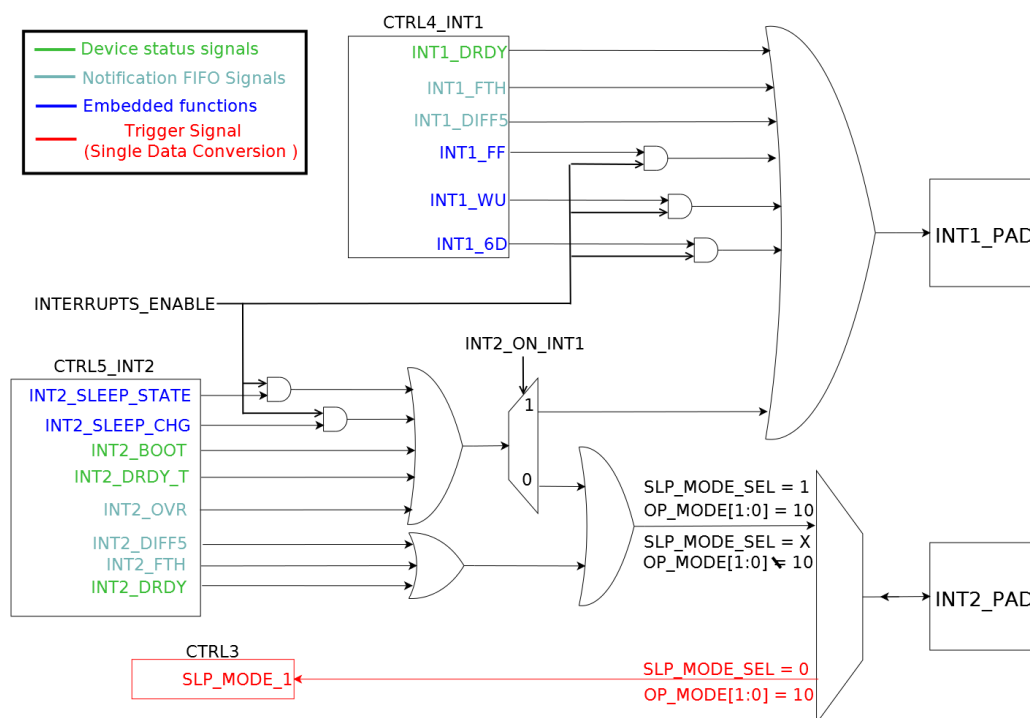
- *Device status signals* (such as data-ready and boot)
- *Embedded function interrupt signals*
- *Notification FIFO signals*

All the *embedded function interrupt signals* are subordinate to the INTERRUPTS_ENABLE bit in register CTRL7. If this bit is set, the embedded functions are enabled and the interrupt signals can be routed to the INT1 and/or INT2 pins; otherwise, if this bit is not set, the embedded functions are disabled. The INT2 pin can also become an input pin when it is used as an *external trigger in single data conversion (on-demand) mode*. In order to configure the device in this mode the user must set bits OP_MODE[1:0] = 10 in register CTRL1 and bit SLP_MODE_SEL = 0 in register CTRL3. It is possible to route all the INT2 pin signals to the INT1 pin by setting bit INT2_ON_INT1 = 1 in register CTRL7.

Note:

Before setting the INTERRUPT_ENABLE bit to 0 in register CTRL7, it is recommended to disable the routing to the interrupt pins INT1/INT2 and to reset the interrupt signal by reading the register ALL_INT_SRC or the dedicated source registers.

Figure 7. Interrupt pin configuration



The description of the interrupt control registers appears below; the default value of their bits is equal to 0, which corresponds to "disable". In order to enable routing a specific interrupt signal to the pin, the corresponding bit has to be set to 1.

Table 13. CTRL4_INT1

b7	b6	b5	b4	b3	b2	b1	b0
INT1_6D	0	INT1_WU	INT1_FF	0	INT1_DIFF5	INT1_FTH	INT1_DRDY

- INT1_6D: 6D recognition is routed to the INT1 pin.
- INT1_WU: wake-up event recognition is routed to the INT1 pin.
- INT1_FF: free-fall event recognition is routed to the INT1 pin.
- INT1_DIFF5: FIFO full recognition is routed to the INT1 pin.
- INT1_FTH: The FIFO threshold event is routed to the INT1 pin.
- INT1_DRDY: accelerometer data-ready is routed to the INT1 pin.

Table 14. CTRL5_INT2

b7	b6	b5	b4	b3	b2	b1	b0
INT2_SLEEP_STATE	INT2_SLEEP_CHG	INT2_BOOT	INT2_DRDY_T	INT2_OVR	INT2_DIFF5	INT2_FTH	INT2_DRDY

- INT2_SLEEP_STATE: enables routing SLEEP_STATE to the INT2 pin.
- INT2_SLEEP_CHG: sleep change status routed to the INT2 pin.
- INT2_BOOT: boot state routed to the INT2 pin.
- INT2_DRDY_T: temperature data-ready is routed to the INT2 pin.
- INT2_OVR: FIFO overrun interrupt is routed to the INT2 pin.
- INT2_DIFF5: FIFO full recognition is routed to the INT2 pin.
- INT2_FTH: FIFO threshold event is routed to the INT2 pin.
- INT2_DRDY: accelerometer data-ready to the INT2 pin.

5.2 Event status

If multiple interrupt signals are routed on the same pin (INTx), the logic level of this pin is the "OR" combination of the selected interrupt signals. In order to know which event has generated the interrupt condition, the application should read the proper status register, which also clears the event.

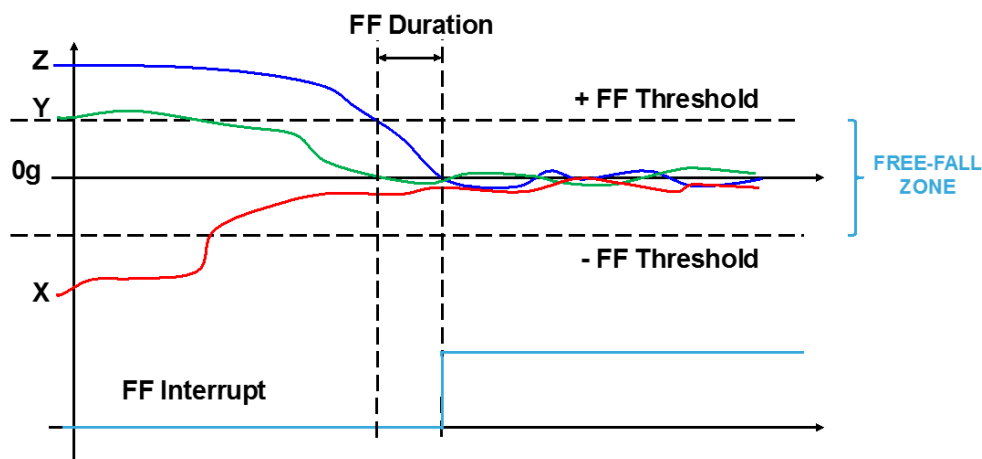
As indicated below, the STATUS register is 'partially' duplicated at address 37h in order to allow a multiple read of consecutive registers.

- STATUS (27h) or STATUS_DUP (37h)
- WAKE_UP_SRC (38h)
- SIXD_SRC (3Ah)
- ALL_INT_SRC (3Bh)

5.3 Free-fall interrupt

Free-fall detection refers to a specific register configuration that allows recognizing when the device is in free-fall: the acceleration measured along all the axes goes to zero. In a real case, a “free-fall zone” is defined around the zero-g level where all the accelerations are small enough to generate the interrupt. Configurable threshold and duration parameters are associated to free-fall event detection: the threshold parameter defines the free-fall zone amplitude; the duration parameter defines the minimum duration of the free-fall interrupt event to be recognized (Figure 8. Free-fall interrupt).

Figure 8. Free-fall interrupt



The free-fall event signal can be routed to the INT1 pin by setting the INT1_FF bit of the CTRL4_INT1 register to 1; it can also be checked by reading the FF_IA bit of the STATUS register.

If latched mode is disabled (LIR bit of CTRL3 is set to 0), the interrupt signal is automatically reset when the free-fall condition is no longer verified. If latched mode is enabled and the free-fall interrupt signal is driven to the interrupt pins, once a free-fall event has occurred and the interrupt pin is asserted, it must be reset by reading the WAKE_UP_SRC or ALL_INT_SRC register. If latched mode is enabled, but the interrupt signal is not driven to the interrupt pins, the latch feature does not take effect (the FF_IA bit in STATUS is reset when the free-fall condition is no longer verified).

The free-fall detection parameters can be modified by configuring the FREE_FALL (contains bits FF_THS[2:0] and FF_DUR[4:0]) and WAKE_UP_DUR (contains MSB of duration parameter - FF_DUR5) registers. The threshold value can be set through the FF_THS[2:0] bits and is described in Table 15. Free-fall threshold value. The values given in this table are valid for any accelerometer full-scale configuration.

Table 15. Free-fall threshold value

FREE_FALL - FF_THS[2:0]	Threshold value
000	~156 mg
001	~219 mg
010	~250 mg
011	~312 mg
100	~344 mg
101	~406 mg
110	~469 mg
111	~500 mg

Duration time is measured in N/ODR, where N is the content of the FF_DUR[5:0] field of the FREE_FALL / WAKE_UP_DUR registers and ODR is the accelerometer data rate.

A basic software routine for free-fall event recognition is given below.

1. Write 53h in CTRL1 // Turn on the accelerometer
// ODR = 100 Hz, power mode 4
2. Write 00h in WAKE_UP_DUR // Set event duration (FF_DUR5 = 0)
3. Write 33h in FREE_FALL // Set FF threshold (FF_THS[2:0] = 011)
// Set six sample event duration (FF_DUR[5:0] = 000110)
4. Write 10h in CTRL4_INT1 // FF interrupt driven to INT1 pin
5. Write 10h in CTRL3 // Latch interrupt
6. Write 20h in CTRL7 // Enable interrupts

The sample code exploits a threshold set to ~312 mg for free-fall recognition and the event is notified by hardware through the INT1 pin. The FF_DUR[5:0] field of the FREE_FALL / WAKE_UP_DUR registers is configured to ignore events that are shorter than $6/ODR = 6/100 \text{ Hz} = 60 \text{ ms}$ in order to avoid false detections.

5.4 Wake-up interrupt

In the AIS2DW12 device the wake-up feature can use the high-pass filter or the offset outputs, this choice can be done through the USR_OFF_ON_WU bit in CTRL7 as illustrated in [Figure 6. Embedded functions](#).

If “offset output” is selected, every axis can have an offset with a different value, writing registers X_OFS_USR, Y_OFS_USR, Z_OFS_USR. Bit weight is defined through the USR_OFF_W bit in register CTRL7.

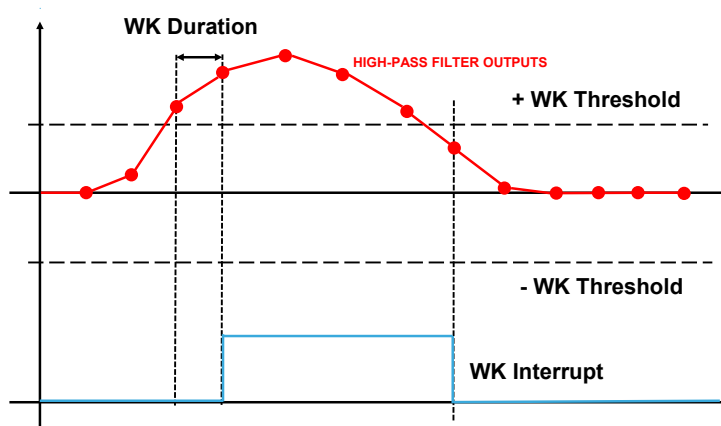
The wake-up interrupt signal is generated if a certain number of consecutive data exceed the configured threshold ([Figure 9. Wake-up event recognition \(using the HP filter\)](#)).

The unsigned threshold value is defined using the WK_THS [5:0] bits of the WAKE_UP_THS register; the value of 1 LSB of these 6 bits depends on the selected accelerometer full scale: $1 \text{ LSB} = FS/64$. The threshold is applied to both positive and negative data: for a wake-up interrupt generation at least one of the three axes must be bigger than the threshold.

The duration parameter defines the minimum duration of the wake-up event to be recognized; its value is set using the WAKE_DUR [1:0] bits of the WAKE_UP_DUR register: 1 LSB corresponds to $1 \cdot ODR$ time, where ODR is the accelerometer output data rate. It is important to appropriately define the duration parameter to avoid unwanted wake-up interrupts due to spurious spikes of the input signal.

This interrupt signal can be driven to the INT1 interrupt pin by setting the INT1_WU bit of the CTRL4_INT1 register to 1; it can also be checked by reading the WU_IA bit of the STATUS register. The X_WU, Y_WU, Z_WU bits of the WAKE_UP_SRC register indicate which axis has triggered the wake-up event.

If latched mode is disabled (LIR bit of CTRL3 is set to 0), the interrupt signal is automatically reset when the filtered data falls below the threshold. If latched mode is enabled and the wake-up interrupt signal is driven to the interrupt pins, once a wake-up event has occurred and the interrupt pin is asserted, it must be reset by reading the WAKE_UP_SRC or ALL_INT_SRC register. The X_WU, Y_WU, Z_WU bits are maintained at the state in which the interrupt was generated until the read is performed, and released at the next ODR cycle. In case the WU_X, WU_Y, WU_Z bits have to be evaluated (in addition to the WU_IA bit), it is recommended to directly read the WAKE_UP_SRC register (do not use the ALL_INT_SRC register for this specific case). If latched mode is enabled but the interrupt signal is not driven to the interrupt pins, the latch feature does not take effect (the WU_IA bit in the WAKE_UP_SRC or ALL_INT_SRC register is reset when the wake-up condition is no longer verified).

Figure 9. Wake-up event recognition (using the HP filter)


The example code that implements the software routine for wake-up event recognition using the HP filter is given below.

- | | | |
|----|--------------------------|---|
| 1. | Write 53h in CTRL1 | // Turn on the accelerometer
// ODR = 100 Hz, power mode 4 |
| 2. | Write 20h in CTRL7 | // Use HP filter, enable interrupts |
| 3. | Write 00h in WAKE_UP_DUR | // No duration |
| 4. | Write 02h in WAKE_UP_THS | // Set wake-up threshold |
| 5. | Write 20h in CTRL4_INT1 | // Wake-up interrupt driven to INT1 pin |

Since the duration time is set to zero, the wake-up interrupt signal is generated for each X,Y,Z data from the HP filter exceeding the configured threshold. The WU_THS field of the WAKE_UP_THS register is set to 000010, therefore the wake-up threshold is 62.5 mg ($= 2 * FS / 64$).

The example code that implements the software routine for the wake-up event using USER OFFSET recognition is given below.

- | | | |
|----|--------------------------|---|
| 1. | Write 2Ch in CTRL7 | // Use X/Y/Z_OFS_USR registers
// X/Y/Z_OFS_USR weight 15.6 mg/LSb
// Enable interrupts |
| 2. | Write 00h in X_OFS_USR | // Set X offset as 0 |
| 3. | Write 00h in Y_OFS_USR | // Set Y offset as 0 |
| 4. | Write 40h in Z_OFS_USR | // Set Z offset as 1 g |
| 5. | Write 00h in WAKE_UP_DUR | // No duration |
| 6. | Write 02h in WAKE_UP_THS | // Set wake-up threshold |
| 7. | Write 20h in CTRL4_INT1 | // Wake-up interrupt driven to INT1 pin |
| 8. | Write 53h in CTRL1 | // Turn on the accelerometer
// ODR = 100 Hz, pPower mode 4 |

Since the duration time is set to zero, the wake-up interrupt signal is generated for each X,Y,Z data from the difference between the data measured and the X_OFS_USR, Y_OFS_USR, Z_OFS_USR registers exceeding the configured threshold. The WU_THS field of the WAKE_UP_THS register is set to 000010, therefore the wake-up threshold is 62.5 mg ($= 2 * FS / 64$).

5.5 6D/4D orientation detection

The AIS2DW12 device provides the capability to detect the orientation of the device in space, enabling easy implementation of energy-saving procedures and automatic image rotation for mobile devices.

5.5.1 6D orientation detection

Six orientations of the device in space can be detected; the interrupt signal is asserted when the device switches from one orientation to another. The interrupt is not reasserted as long as the position is maintained.

6D interrupt is generated when only one axis exceeds a selected threshold and the acceleration values measured from the other two axes are lower than the threshold: the ZH, ZL, YH, YL, XH, XL bits of the SIXD_SRC register indicate which axis has triggered the 6D event.

In more detail:

Table 16. SIXD_SRC register

b7	b6	b5	b4	b3	b2	b1	b0
0	6D_IA	ZH	ZL	YH	YL	XH	XL

- 6D_IA is set high when the device switches from one orientation to another.
- ZH (YH, XH) is set high when the face perpendicular to the Z (Y,X) axis is almost flat and the acceleration measured on the Z (Y,X) axis is positive and in the absolute value bigger than the threshold.
- ZL (YL, XL) is set high when the face perpendicular to the Z (Y,X) axis is almost flat and the acceleration measured on the Z (Y,X) axis is negative and in the absolute value bigger than the threshold.

The 6D_THS[1:0] bits of the SIXD_THS register are used to select the threshold value used to detect the change in device orientation. The threshold values given in the following table are valid for each accelerometer full-scale value.

Table 17. Threshold for 4D/6D function

6D_THS[1:0]	Threshold value [degrees]
00	80
01	70
10	60
11	50

This interrupt signal can be driven to the INT1 interrupt pin by setting the INT1_6D bit of the CTRL4_INT1 register to 1; it can also be checked by reading the 6D_IA bit of the SIXD_SRC register.

If latched mode is disabled (LIR bit of CTRL3 is set to 0), the interrupt signal is active only for 1/ODR[s] then it is automatically deasserted (ODR is the accelerometer output data rate). If latched mode is enabled and the 6D interrupt signal is driven to the interrupt pins, once an orientation change has occurred and the interrupt pin is asserted, a read of the SIXD_SRC or ALL_INT_SRC register clears the request and the device is ready to recognize a different orientation. The XL, XH, YL, YH, ZL, ZH bits are not affected by the LIR configuration: they correspond to the current state of the device when the SIXD_SRC register is read. If latched mode is enabled but the interrupt signal is not driven to the interrupt pins, the latch feature does not take effect.

Referring to the six possible cases illustrated in the following figure, the content of the SIXD_SRC register for each position is shown in Table 18. SIXD_SRC register for 6D positions.

Figure 10. 6D recognized orientations

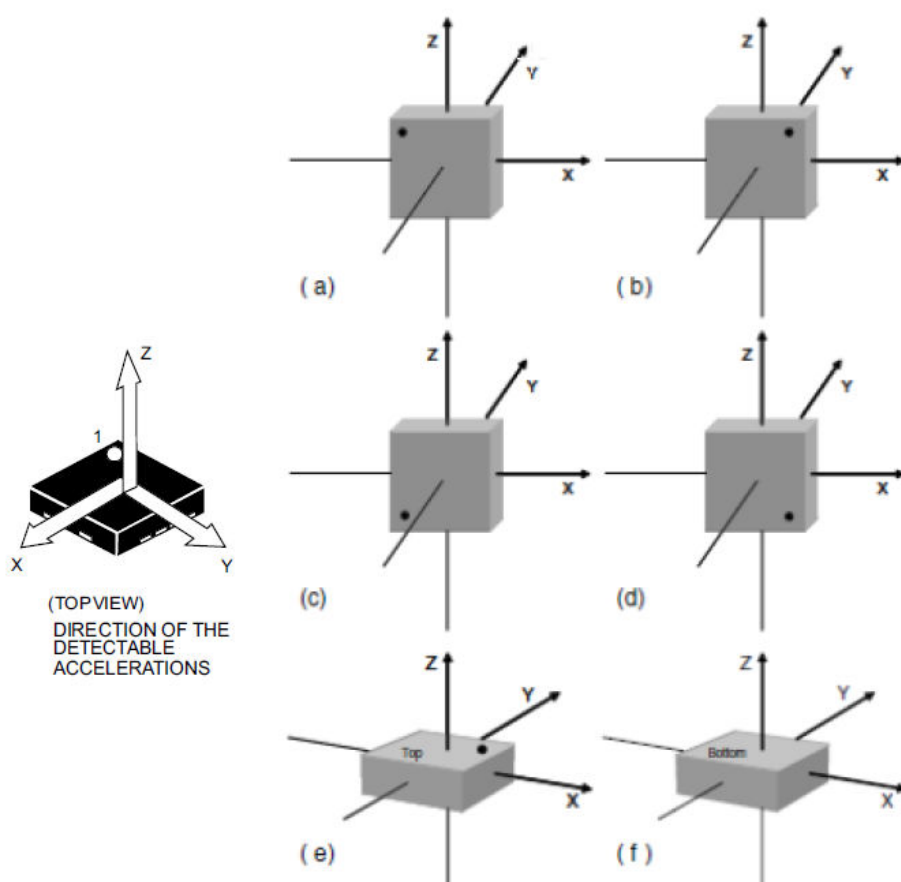


Table 18. SIXD_SRC register for 6D positions

Case	6D_IA	ZH	ZL	YH	YL	XH	XL
(a)	1	0	0	0	0	0	1
(b)	1	0	0	0	1	0	0
(c)	1	0	0	1	0	0	0
(d)	1	0	0	0	0	1	0
(e)	1	1	0	0	0	0	0
(f)	1	0	1	0	0	0	0

The following example implements a software routine for 6D orientation detection:

1. Write 53h in CTRL1 // Turn on the accelerometer
// ODR = 100 Hz, power mode 4
2. Write 20h in CTRL7 // Do not use low-pass filter for 6D, enable interrupts
3. Write 40h in SIXD_THS // Set 6D threshold (6D_THS[1:0] = 10 = 60 degrees)
4. Write 80h in CTRL4_INT1 // 6D interrupt driven to INT1 pin

5.5.2 4D orientation detection

The 4D direction function is a subset of the 6D function especially defined to be implemented in mobile devices for portrait and landscape computation. It can be enabled by setting the 4D_EN bit of the SIXD_THS register to 1. In this configuration, Z-axis position detection is disabled, therefore reducing position recognition to cases (a), (b), (c), and (d) of Table 18. SIXD_SRC register for 6D positions.

5.6 Activity/inactivity recognition

The activity/inactivity recognition function allows reducing system power consumption and developing new smart applications.

The activity/inactivity function is enabled by setting the SLEEP_ON bit of WAKE_UP_THS (34h) register to 1. If the sleep state condition is detected, the AIS2DW12 automatically goes to 12.5 Hz ODR in the mode previously selected by the PW_MODE[1:0] bits in CTRL1 (20h). The AIS2DW12 wakes up from the sleep state as soon as a wake-up event has been detected, switching to the operating mode and ODR configured in the CTRL1 (20h) register.

With this feature the system may be efficiently switched from low-power consumption to full performance and vice versa depending on user-selectable acceleration events, thus ensuring power saving and flexibility.

The activity/inactivity recognition function can use the high-pass filter or the offset outputs, this choice can be done through the USR_OFF_ON_WU bit in CTRL7 as illustrated in Figure 6. Embedded functions.

If "offset output" is selected, each axis can be offset with a different value, writing registers X_OFS_USR, Y_OFS_USR, Z_OFS_USR. The bit weight is defined through the USR_OFF_W bit in register CTRL7.

This function can be fully programmed by the user in terms of the expected amplitude and timing of the high-pass filtered data by means of a dedicated set of registers (Figure 11. Activity/Inactivity recognition (using the HP filter)).

The unsigned threshold value is defined using the WK_THS[5:0] bits in the WAKE_UP_THS register; the value of 1 LSB of these 6 bits depends on the selected accelerometer full scale: 1 LSB = 1 / 64 of FS. The threshold is applied to both positive and negative high-pass filtered data.

When a certain number of consecutive X,Y,Z high-pass filtered data is smaller than the configured threshold, the ODR [3:0] bits of the CTRL1 register are bypassed (inactivity) and the accelerometer is internally set to 12.5 Hz although the content of CTRL1 is left untouched. The duration of the inactivity status to be recognized is defined by the SLEEP_DUR[3:0] bits of the WAKE_UP_DUR register: 1 LSB corresponds to 512/ODR time, where ODR is the accelerometer output data rate.

During the inactivity status of the device, the SLEEP_STATE bit in STATUS is set high. This bit can be routed to the INT2 pin setting both the INT2_SLEEP_STATE and INT2_SLEEP_STATE_CHG bits to 1 in CTRL5_INT2. Note that this signal is not compatible with "latched notification mode", the LIR bit of CTRL3 should be set to 0.

Every time the device status changes from activity to inactivity or vice versa, the SLEEP_CHANGE_IA bit in ALL_INT_SRC is set for about 1.2 ms. This bit can be routed on the INT2 pin using the INT2_SLEEP_CHG bit in CTRL5_INT2.

The typical duration of the sleep change event pulse on the interrupt pin depends on the selected power mode.

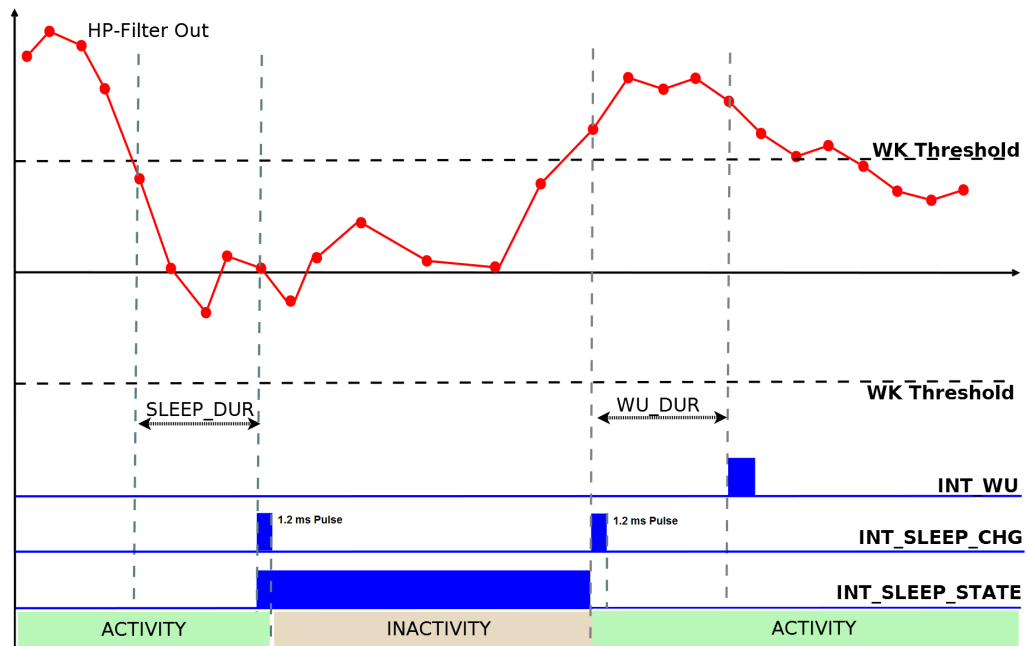
Table 19. Pulse duration on interrupt pin

Power mode	Pulse duration
Power mode 1	1.20 ms
Power mode 2	1.70 ms
Power mode 3	2.30 ms
Power mode 4	3.55 ms

When a single sample of high-pass filtered data on one axis becomes bigger than the threshold, the CTRL1 register settings are immediately restored (activity). The wake-up interrupt event can be delayed in function of the value of the WU_DUR[1:0] bits of the WAKE_UP_DUR register: 1 LSB corresponds to 1/ODR time, where ODR is the accelerometer output data rate. In order to generate the interrupt at the same time as the inactivity/activity event, WU_DUR[1:0] have to be set to 0.

When the wake-up event is detected, the interrupt is set high for 1/ODR period, then it is automatically deasserted (the WU_IA event on the pin must be routed by setting the INT1_WU bit of CTRL4_INT1 register to 1).

Figure 11. Activity/Inactivity recognition (using the HP filter)



The code provided below is a basic routine for activity/inactivity detection implementation.

1. Write 53h in CTRL1 // Turn on the accelerometer
// ODR = 100 Hz, power mode 4
2. Write 42h in WAKE_UP_DUR // Set duration for inactivity detection
// Set duration for wake-up detection
3. Write 42h in WAKE_UP_THS // Set activity/inactivity threshold
// Enable activity/inactivity detection
4. Write 20h in CTRL4_INT1 // Activity (wake-up) interrupt driven to INT1 pin
5. Write 20h in CTRL7 // Enable interrupts

In this example the WU_THS field of the WAKE_UP_THS register is set to 000010, therefore the activity/inactivity threshold is 62.5 mg ($= 2 * FS / 64$).

Before inactivity detection, the X,Y,Z high-pass filtered data must be smaller than the configured threshold for a period of time defined by the SLEEP_DUR field of the WAKE_UP_DUR register: this field is set to 0010, corresponding to 10.24 s ($= 2 * 512 / ODR$). After this period of time has elapsed, the accelerometer ODR is internally set to 12.5 Hz.

The activity status is detected and the CTRL1 register settings immediately restored if the high-pass filtered data of (at least) one axis is bigger than the threshold and the wake-up interrupt was notified after an interval defined by the WU_DUR field of the WAKE_UP_DUR register: this field is set to 10, corresponding to 20 ms ($= 2 * 1 / ODR$).

The following routine describes how to route the sleep change event to the INT2 pin.

- | | |
|-----------------------------|--|
| 1. Write 53h in CTRL1 | // Turn on the accelerometer |
| | // ODR = 100 Hz, power mode 4 |
| 2. Write 02h in WAKE_UP_DUR | // Set duration for inactivity detection |
| 3. Write 42h in WAKE_UP_THS | // Set activity/inactivity threshold |
| | // Enable activity/inactivity detection |
| 4. Write 40h in CTRL5_INT2 | // Sleep change interrupt driven to INT2 pin |
| 5. Write 20h in CTRL7 | // Enable interrupts |

This example is similar to the previous one but the "sleep change" event is routed to the INT2 pin.

5.7 Stationary/motion detection

Stationary/motion detection is a particular case of the activity/inactivity functionality in which no ODR / power mode changes occur when a sleep condition (equivalent to a stationary condition) is detected. Stationary/motion detection is activated by setting the STATIONARY bit to 1 in WAKE_UP_DUR. If both the STATIONARY bit and SLEEP_ON bit in the WAKE_UP_THS register are set to 1, stationary/motion detection is selected.

5.8 Boot status

After the device is powered up, the AIS2DW12 performs a 20 ms boot procedure to load the trimming parameters (register addresses: 02h; from 07h to 0Bh; from 10h to 1Fh). After the boot is completed, the accelerometer is automatically configured in power-down mode.

During the boot time, the registers are not accessible.

After power-up, the trimming parameters can be reloaded by setting the BOOT bit of the CTRL2 register to 1.

No toggle of the device power lines is required and the content of the device control registers is not modified. If a reset to the default value of the control registers is required (registers addresses: from 20h to 25h; 2Eh; from 30h to 36h; from 3Ch to 3Fh), it can be performed by setting the SOFT_RESET bit of the CTRL2 register to 1. The software reset procedure can take 5 μ s.

The boot status signal can be driven to the INT2 interrupt pin by setting the INT2_BOOT bit of the CTRL5_INT2 register to 1: the signal goes to 1 while a boot is taking place, and returns to 0 when it is done.

The flow must be performed serially (from ANY operating mode) as shown in the example below:

1. Set the SOFT_RESET bit to 1.
2. Wait 5 μ s (or wait until the SOFT_RESET bit of the CTRL2 register returns to 0).
3. Set the BOOT bit to 1.
4. Wait 20 ms.

In order to avoid conflicts, the reboot and the software reset must not be executed at the same time (do not set at the same time both the BOOT bit and SOFT_RESET bit to 1 in the CTRL2 register).

6 First-in first-out (FIFO) buffer

In order to limit intervention by the host processor and facilitate postprocessing data for recognition of events, the AIS2DW12 embeds a first-in, first-out buffer (FIFO) for each of the three output channels, X, Y, and Z.

FIFO use allows consistent power saving for the system, it can wake up only when needed and burst the significant data out from the FIFO.

The FIFO buffer can work according to five different modes that guarantee a high level of flexibility during application development: bypass mode, FIFO mode, continuous mode, bypass-to-continuous and continuous-to-FIFO mode.

A programmable watermark level and the FIFO full event can be enabled to generate dedicated interrupts on the INT1 or INT2 pins.

6.1 FIFO description

The FIFO buffer is able to store up to 32 acceleration samples stored with the resolution according to bits OP_MODE[1:0] and PW_MODE[1:0] in register CTRL1.

The data sample set consists of 6 bytes (XI, Xh, Yl, Yh, Zl, and Zh) and they are released to the FIFO at the selected output data rate defined by ODR[3:0] in register CTRL1.

The new sample set is placed in the first empty FIFO slot until the buffer is full, therefore, the oldest value is overwritten.

Table 20. FIFO buffer full representation (32nd sample set stored)

Output registers	28h	29h	2Ah	2Bh	2Ch	2Dh
	XI	Xh	Yl	Yh	Zl	Zh
FIFO index	FIFO sample set					
FIFO(0)	XI(0)	Xh(0)	Yl(0)	Yh(0)	Zl(0)	Zh(0)
FIFO(1)	XI(1)	Xh(1)	Yl(1)	Yh(1)	Zl(1)	Zh(1)
FIFO(2)	XI(2)	Xh(2)	Yl(2)	Yh(2)	Zl(2)	Zh(2)
FIFO(3)	XI(3)	Xh(3)	Yl(3)	Yh(3)	Zl(3)	Zh(3)
...
FIFO(30)	XI(30)	Xh(30)	Yl(30)	Yh(30)	Zl(30)	Zh(30)
FIFO(31)	XI(31)	Xh(31)	Yl(31)	Yh(31)	Zl(31)	Zh(31)

Table 21. FIFO buffer full representation (33rd sample set stored and 1st sample discarded)

Output registers	28h	29h	2Ah	2Bh	2Ch	2Dh
	XI	Xh	Yl	Yh	Zl	Zh
FIFO index	Sample set					
FIFO(0)	XI(1)	Xh(1)	Yl(1)	Yh(1)	Zl(1)	Zh(1)
FIFO(1)	XI(2)	Xh(2)	Yl(2)	Yh(2)	Zl(2)	Zh(2)
FIFO(2)	XI(3)	Xh(3)	Yl(3)	Yh(3)	Zl(3)	Zh(3)
FIFO(3)	XI(4)	Xh(4)	Yl(4)	Yh(4)	Zl(4)	Zh(4)
...
FIFO(31)	XI(32)	Xh(32)	Yl(32)	Yh(32)	Zl(32)	Zh(32)

Table 20 represents the FIFO full status when 32 samples are stored in the buffer while Table 21 represents the next step when the 33rd sample is inserted into FIFO and the 1st sample is overwritten. The new oldest sample set is made available in the output registers.

When FIFO is enabled and the mode is different from bypass, the AIS2DW12 output registers (28h to 2Dh) always contain the oldest FIFO sample set.

6.2 FIFO registers

The FIFO buffer is managed by two different registers, one allows enabling and configuring the FIFO behavior, the other one provides information about the buffer status.

A few other registers are used to route FIFO events to the INT1 and INT2 pins to interrupt the application processor. These are discussed in [Section 6.3 FIFO interrupts](#).

6.2.1 FIFO_CTRL (2Eh)

The FIFO_CTRL register contains the mode in which the FIFO is set. At reset, by default, the FIFO mode is bypass, which means that the FIFO is off; the FIFO is enabled and starts storing the samples as soon as the mode is set to a mode other than bypass.

Table 22. FIFO_CTRL register

b7	b6	b5	b4	b3	b2	b1	b0
FMode2	FMode1	FMode0	FTH4	FTH3	FTH2	FTH1	FTH0

The FMode[2:0] bits select the FIFO buffer behavior:

1. FMode[2:0] = 000: bypass mode (FIFO turned off)
2. FMode[2:0] = 001: FIFO mode
3. FMode[2:0] = 011: continuous-to-FIFO mode
4. FMode[2:0] = 100: bypass-to-continuous mode
5. FMode[2:0] = 110: continuous mode

FTH[4:0] bits are discussed in [Section 6.3.1 FIFO threshold](#).

6.2.2 FIFO_SAMPLES (2Fh)

This register is updated at every ODR and provides information about the FIFO buffer status.

Table 23. FIFO_SAMPLES register

b7	b6	b5	b4	b3	b2	b1	b0
FIFO_FTH	FIFO_OVR	Diff5	Diff4	Diff3	Diff2	Diff1	Diff0

- FIFO_FTH bit is set high when the FIFO content is greater than or equal to the watermark level. This flag can be routed to the INT1 or INT2 pin (see [Section 6.3 FIFO interrupts](#)).
- FIFO_OVR bit is set high when the first sample is overwritten after the FIFO buffer is full. This means that the FIFO buffer contains 32 unread samples. The FIFO_OVR bit is reset when the first sample set has been read.
- Diff5 bit is used together with bits Diff[4:0] to provide information of how many FIFO entries are used (000000 means FIFO empty, 100000 means FIFO full). This flag can be routed to the INT1 or INT2 pin (see [Section 6.3 FIFO interrupts](#)).

The update of the register content is synchronous with the FIFO write and read operation.

Table 24. FIFO_SAMPLES behavior assuming FTH[4:0] = 15

FIFO_FTH	Diff5 (FIFO_FULL)	FIFO_OVR	Diff[4:0]	Unread FIFO samples	Timing
0	0	0	00000	0	t0
0	0	0	00001	1	t0 + 1/ODR
0	0	0	00010	2	t0 + 2/ODR
...
0	0	0	01110	14	t0 + 14/ODR
1	0	0	01111	15	t0 + 15/ODR
...
1	0	0	11111	31	t0 + 31/ODR
1	1	0	00000	32	t0 + 32/ODR
1	1	1	00000	32	t0 + 33/ODR

6.3 FIFO interrupts

There are three specific FIFO events that can be routed to the pins in order to interrupt the main processor: FIFO threshold, FIFO full, and FIFO overrun.

All FIFO events can be routed to the INT1 and INT2 pins.

6.3.1 FIFO threshold

The FIFO threshold is a configurable feature that can be used to generate a specific interrupt in order to know when the FIFO buffer contains at least the number of samples defined as the threshold level. The user can select the desired level in a range from 0 to 31 using the FTH[4:0] field in the FIFO_CTRL register.

If the number of entries in FIFO (Diff[5:0]) is greater than or equal to the value programmed in FTH[4:0], the FIFO_FTH bit is set high in the FIFO_SAMPLES register.

Diff[5:0] increases by one step at the ODR frequency and decreases by one step every time that a sample set read is performed by the user.

The threshold flag (FIFO_FTH) can be routed to the INT1 and INT2 pins to provide a dedicated interrupt for the application processor that can, as a consequence, consume less power between interrupts. The INT1_FTH bit of CTRL4_INT1 register and the INT2_FTH bit of CTRL5_INT2 register are dedicated to this task.

6.3.2 FIFO full

It is possible to configure the device to generate an interrupt whenever the FIFO becomes full. To do so, just set the INT1_DIFF5 bit of the CTRL4_INT1 register to 1 (or the INT2_DIFF5 bit of the CTRL5_INT2 register to 1). To avoid losing samples, the FIFO read operation must start and complete inside 1 ODR window.

6.3.3 FIFO overrun

It is possible to configure the device to generate an interrupt if the overrun event occurs in FIFO. To do so, just set the INT2_OVR bit of the CTRL5_INT2 register to 1.

6.4 FIFO modes

The AIS2DW12 FIFO buffer can be configured to operate in five different modes selectable by the FMODE[2:0] field in the FIFO_CTRL register. Available configurations ensure a high-level of flexibility and extend the number of usable functions in application development.

Bypass, FIFO, continuous, bypass-to-continuous, and continuous-to-FIFO modes are described in the following paragraphs.

6.4.1 Bypass mode

When bypass mode is enabled, the FIFO is not operational: buffer content is cleared, output registers (0x28 to 0x2D) are frozen at the last value loaded, and the FIFO buffer remains empty until another mode is selected.

Bypass mode is activated by setting the FMODE[2:0] field to 000 in the FIFO_CTRL register.

Bypass mode must be used in order to stop and reset the FIFO buffer when a different mode is operating. Note that placing the FIFO buffer in bypass mode clears the whole buffer content.

6.4.2 FIFO mode

In FIFO mode, the buffer continues filling until full (32 sample sets stored). As soon as the FIFO_OVR flag goes to 1, the FIFO stops collecting data and its content remains unchanged until a different mode is selected.

FIFO mode is activated by setting the FMODE[2:0] field to 001 in the FIFO_CTRL register.

By selecting this mode, FIFO starts data collection and Diff[5:0] changes according to the number of samples stored. At the end of the procedure, the FIFO_OVR flag rises to 1, and data can then be retrieved, performing a 32 sample set read from the output registers. Communication speed is not so important in FIFO mode because data collection is stopped and there is no risk of overwriting acquired data. Before restarting FIFO mode, at the end of the read procedure it is necessary to exit bypass mode.

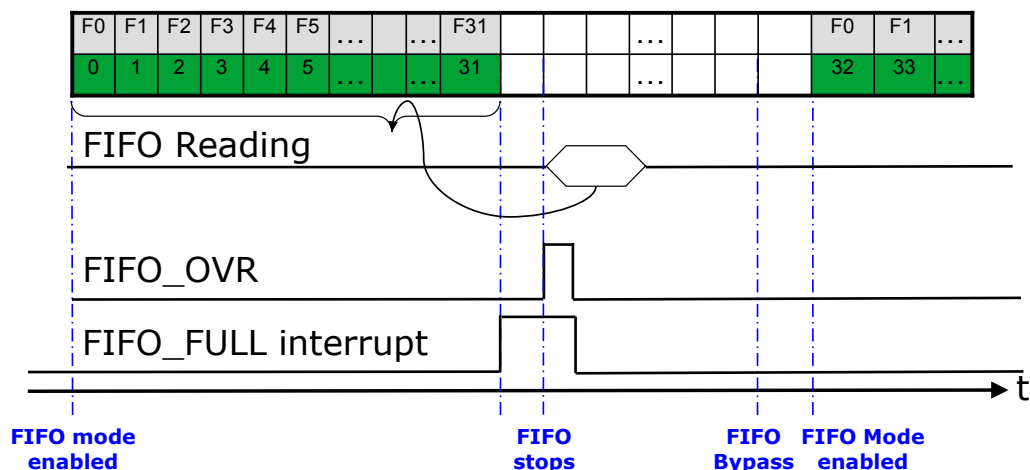
In order to serve the FIFO full (Diff5 bit) event as soon as possible, it is recommended to route it to the pin in order to generate an interrupt, which is then be managed by a specific handler:

1. Set INT1_DIFF5 to 1: enables FIFO_FULL interrupt.
2. Set FMode[2:0] = 001: enables FIFO mode.

When the FIFO_FULL interrupt is generated or the FIFO_OVR bit is high (polling mode):

1. Read data from the accelerometer output registers.

Figure 12. FIFO mode behavior



As indicated in Figure 12, when FIFO mode is enabled, the buffer starts to collect data and fills all 32 slots (from F0 to F31) at the selected output data rate. When the buffer is full, as the next sample comes in and overrides the buffer, the FIFO_OVR bit goes high and data collection is permanently stopped; the user can decide to read FIFO content at any time because it is maintained unchanged until bypass mode is selected. The read procedure may be performed inside an interrupt handler triggered by a FIFO FULL condition (Diff5) and it is composed of a 32 sample set of 6 bytes for a total of 192 bytes and retrieves data starting from the oldest sample stored in FIFO (F0). The FIFO_OVR bit is reset when the first sample set has been read. The bypass mode setting resets FIFO and allows the user to enable FIFO mode again.

6.4.3 Continuous mode

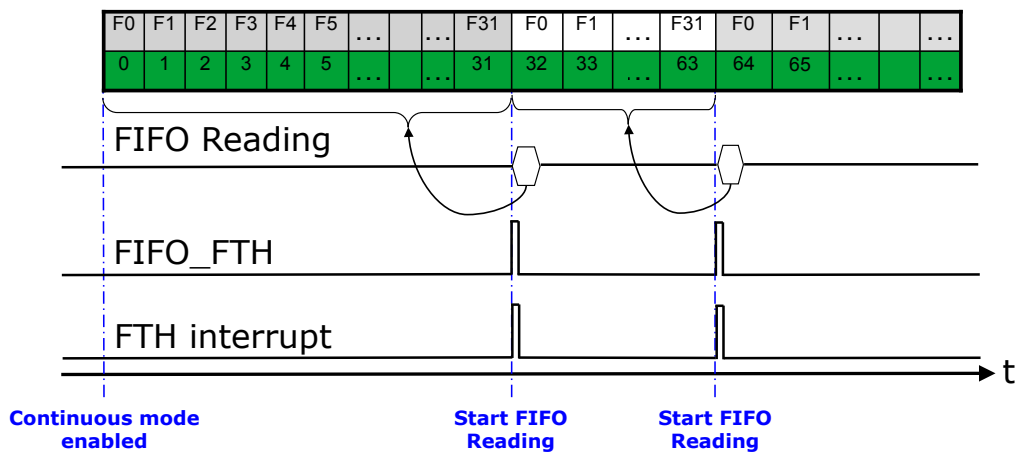
In continuous mode FIFO continues filling, when the buffer is full, the FIFO index restarts from the beginning and older data is replaced by current data. The oldest values continue to be overwritten until a read operation frees FIFO slots. The reading speed of the host processor is most important in order to free slots faster than new data is made available. FMODE[2:0] in bypass configuration is used to stop this mode.

Follow these steps for FIFO continuous configuration, which sets a threshold to generate an interrupt to trigger a read by the application processor:

1. Set FTH[4:0] to 31.
2. Set INT1_FTH to 1: enables FIFO threshold interrupt.
3. Activate continuous mode by setting the FMode[2:0] field to 110 in the FIFO_CTRL register (2Eh).

When the FTH interrupt is generated, data is read from the accelerometer output registers.

Figure 13. Continuous mode with interrupt trigger



As indicated in [Figure 13](#), when continuous mode is enabled, the FIFO buffer continuously fills (from F0 to F31) at the selected output data rate. When the buffer is full, the FTH interrupt (as well as the FIFO_FULL condition indicated by the Diff5 bit in FIFO_SAMPLES (2Fh), which might also be used to trigger an interrupt) goes high, and the application processor may read all FIFO samples (32 * 6 bytes) as soon as possible to avoid loss of data and to limit intervention by the host processor, which increases system efficiency. See [Section 6.5 Retrieving data from FIFO](#) for more details on FIFO reading speed.

When a read command is sent to the device, the content of the output registers is moved to the SPI/I²C register and the current oldest FIFO value is shifted into the output registers in order to allow the next read operation.

6.4.4 Continuous-to-FIFO mode

This mode is a combination of the continuous and FIFO modes previously described. In continuous-to-FIFO mode, the FIFO buffer starts operating in continuous mode and switches to FIFO mode when the selected interrupt (that is, wake-up, free-fall, 6D/4D, or any combination of them) occurs.

This mode can be used in order to analyze the history of samples that generated an interrupt; the standard operation is to read FIFO content when a FIFO mode is triggered and the FIFO buffer is full and stopped.

Follow these steps for continuous-to-FIFO mode configuration:

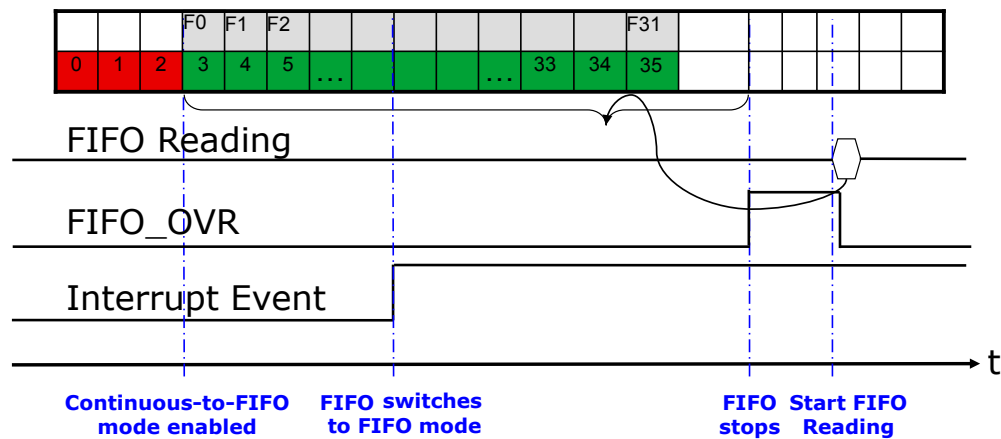
1. Configure the desired interrupt generator by following the instructions in [Section 5 Interrupt generation and embedded functions](#) (be sure it is latched).
2. Activate continuous-to-FIFO mode by setting the FMode[2:0] field to 011 in the FIFO_CTRL register (2Eh).

Note:

When the requested event takes place, the FIFO mode change is triggered if and only if the event flag is routed to the INT1 or INT2 pin.

While in continuous mode the FIFO buffer continues filling; when the requested event takes place the FIFO mode changes; then, as soon as the buffer becomes full, the FIFO_OVR bit is set high and the next samples overwrite the oldest and the FIFO stops collecting data (see figure below).

Figure 14. Continuous-to-FIFO mode: interrupt latched and nonlatched



6.4.5 Bypass-to-continuous mode

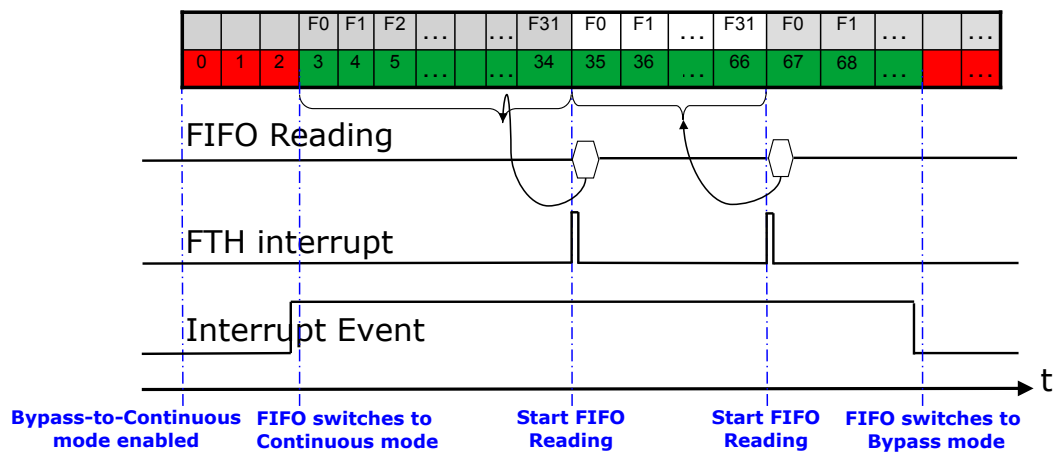
This mode is a combination of the bypass and continuous modes previously described. In bypass-to-continuous mode, the FIFO buffer starts in bypass mode and switches to continuous mode when the selected interrupt (that is, wake-up, free-fall, 6D/4D, or any combination of these) occurs.

Follow these steps for bypass-to-continuous mode configuration:

1. Configure the desired interrupt generator by following the instructions in [Section 5 Interrupt generation and embedded functions](#) (be sure it is latched).
2. Set FTH[4:0] to 31.
3. Set INT1_FTH to 1: enables FIFO threshold interrupt.
4. Activate bypass-to-continuous mode by setting the FMode[2:0] field to 100 in the FIFO_CTRL register (2Eh).

When the FTH interrupt is generated, data is read from the accelerometer output registers.

Figure 15. Bypass-to-continuous mode



As indicated in the previous figure, the FIFO is initially in bypass mode, so no samples enter in the FIFO buffer. As soon as an event occurs (for example, a wake-up or a free-fall event) the FIFO switches to continuous mode and starts to store the samples at the configured data rate. When the programmed threshold is reached, the FTH interrupt goes high, and the application processor may start reading all FIFO samples (32 * 6 bytes) as soon as possible to avoid loss of data.

If the FIFO_OVR flag was set, it goes to 0 as soon as the first FIFO set is read, creating space for new data. Since the FIFO is still in continuous mode, the FIFO eventually reaches the threshold again and the situation repeats.

Finally, either the interrupt event is cleared or the FIFO directly enters bypass mode and then it stops collecting data.

6.5 Retrieving data from FIFO

When the FIFO mode is different from bypass, reading the output registers (28h to 2Dh) returns the oldest FIFO sample set.

Whenever the output registers are read, their content is moved to the SPI/I²C output buffer. FIFO slots are ideally shifted up one level in order to release room for receiving a new sample and the output registers load the current oldest value stored in the FIFO buffer.

The whole FIFO content is retrieved by performing 32 read operations from the accelerometer output registers. The size of the data stored in FIFO is dependent on the selected power mode. Every other read operation returns the same last value until a new sample set is available in the FIFO buffer.

Data can be retrieved from FIFO using every read byte combination in order to increase application flexibility (ex: 192 single byte read, 32 reads of 6 bytes, 1 multiple read of 192 bytes, and so forth).

It is recommended to read all FIFO slots in a multiple byte read of 192 bytes (6 output registers by 32 slots). In order to minimize communication between the master and slave, the read address may be automatically incremented by the device by setting the IF_ADD_INC bit of the CTRL2 register to 1; the device rolls back to 0x28 when register 0x2D is reached.

The I²C speed is lower than SPI and it needs about 29 clock pulses to start communication (start, slave address, register address+write, restart, register address+read) plus an additional 9 clock pulses for every byte to read (total of 83 clock pulses). So, in the case of standard I²C mode being used (max rate 100 kHz), a single sample set read takes 830 µs while a total FIFO download takes about 17.57 ms (29 + 9 * 192 clock pulses).

In the case of the SPI, instead, 8 clock pulses are required only once at the very beginning to get started (for the register address, including the R/W bit) plus an additional 8 clock pulses for every byte to read. With a 2 MHz clock a single sample set read would take 28 µs, while a total FIFO download takes about 772 µs.

If this recommendation were followed, using a standard I²C (100 kHz) the complete FIFO read (17.57 ms) takes 28/ODR with ODR at 1600 Hz. Using a SPI @ 2 MHz (10 MHz is the maximum supported by the device) the complete FIFO read would take about two periods of data generation (2*1/ODR) with ODR at 1600 Hz.

So, in order to not lose samples, the application reads samples before the FIFO becomes full, setting a threshold and using the FTH interrupt (see [Section 6.3 FIFO interrupts](#)).

Table 25. Example: threshold function of ODR

ODR (Hz)	FTH_THS (I ² C @ 100 kHz)	FTH_THS (I ² C @ 400 kHz)	FTH_THS (SPI @ 2 MHz)
50	32	32	32
100	17	32	32

7 Temperature sensor

The AIS2DW12 is provided with an internal temperature sensor that is suitable for ambient temperature measurement.

If the sensor is in power-down mode, the temperature sensor is off and shows the last value measured.

Bit DRDY_T in STATUS_DUP (37h) is set high when a new set of data is available and is reset when one of the temperature data outputs (OUT_T_H or OUT_T) is read. The DRDY_T bit can be routed on the INT2 pin through bit INT2_DRDY_T of the CTRL5_INT2 register.

The temperature DRDY interrupt can be pulsed using the DRDY_PULSED bit of the CTRL7 register: the pulse duration is 78 μ s (typical). Pulsed mode is not applied to the DRDY_T bit, which is always latched.

The temperature data is represented as a number of 12 bits in two's complement format, left-aligned in the OUT_T_L and OUT_T_H registers. A duplicated value of OUT_T_H in register OUT_T is also available in order to provide 8 bits in two's complement format, temperature sequentially readable with the sensor outputs. See the table below for temperature sensor details.

Table 26. Temperature sensor characteristics

Symbol	Parameter	Min.	Typ. ⁽¹⁾	Max.	Unit
TsDr	Temperature sensor output change vs. temperature		1 ⁽²⁾		LSB/°C
			16 ⁽³⁾		
TODR	Temperature refresh rate for accelerometer ODRs equal to 100 Hz and 50 Hz		50		Hz
	Temperature refresh rate for accelerometer ODR equal to 25 Hz		25		
	Temperature refresh rate for accelerometer ODR equal to 12.5 Hz		12.5		
	Temperature refresh rate for accelerometer ODR equal to 1.6 Hz		1.6		

1. Typical specifications are not guaranteed.

2. 8-bit resolution (that is, when using the OUT_T register)

3. 12-bit resolution (that is, when using the OUT_T_L and OUT_T_H registers)

7.1 Example of temperature data calculation

The following table provides a few basic examples of the data that is read from the temperature data registers at different ambient temperature values. The values listed in this table are given under the hypothesis of perfect device calibration (that is, no offset, no gain error, and so forth).

Table 27. Content of output data registers vs. temperature

Temperature values	OUT_T (26h)	OUT_T_H (0Eh)	OUT_T_L (0Dh)
23.5°C	FEh	FEh	80h
25.0°C	00h	00h	00h
26.5°C	01h	01h	80h

8 Self-test

The embedded self-test functions allow checking device functionality without moving it.

When the accelerometer self-test is enabled, an actuation force is applied to the sensor, leading to a deflection of the moveable part of the sensor. In this case, the sensor outputs exhibit a change in their DC levels that are related to the selected full scale through the sensitivity value.

The accelerometer self-test function is off when the ST[2:1] bits of the CTRL3 register are programmed to 00; it is enabled when the ST[2:1] bits are set to 01 (positive sign self-test) or 10 (negative sign self-test).

When the accelerometer self-test is activated, the sensor output level is given by the algebraic sum of the data produced by the electrostatic test-force and gravity.

The procedure consists of:

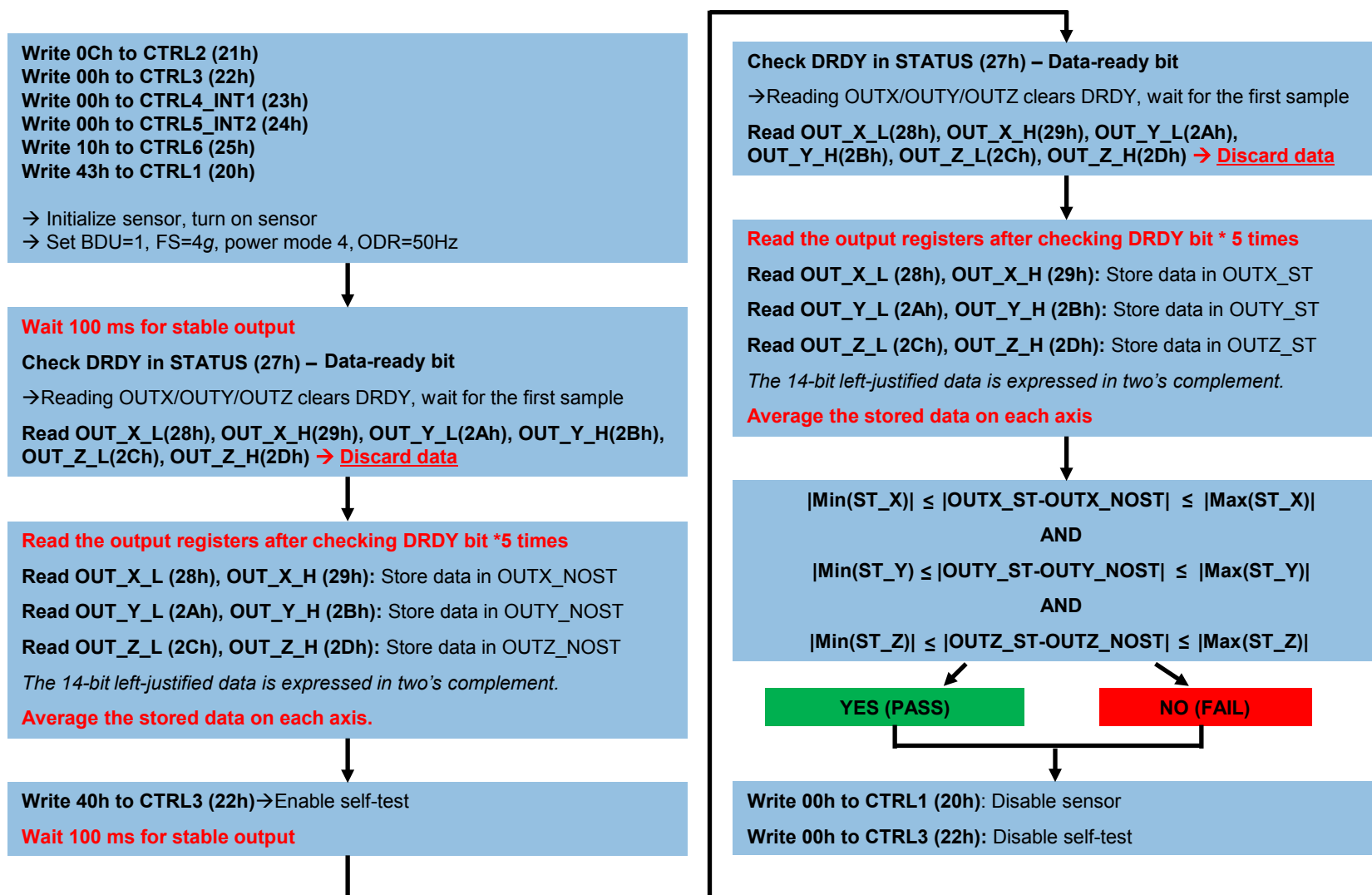
1. Enabling the accelerometer
2. Averaging five samples before enabling the self-test
3. Averaging five samples after enabling the self-test
4. Computing the difference in absolute value for each axis and verifying that it falls within a given range. The min and max values are provided in the datasheet.

The complete accelerometer self-test procedure is indicated in [Figure 16. Accelerometer self-test procedure](#).

Notes:

1. *Keep the device still during the self-test procedure.*
2. *The full scale and data rate used in the self-test procedure are not mandatory but recommended.*
3. *Refer to the datasheet for minimum and maximum values.*

Figure 16. Accelerometer self-test procedure



Note: The wait time of 100 ms is not mandatory but recommended. In any case, the settling time should be taken into account.

Revision history

Table 28. Document revision history

Date	Version	Changes
21-Jan-2021	3	Updated Section 3.5 High-pass filter configuration Updated Section 5.3 Free-fall interrupt
01-Sep-2023	4	Updated Section 3 Operating modes Updated Figure 4. High-pass filter in normal and reference mode Updated Section 4.1 Startup sequence Added Note to Section 5.1 Interrupt pin configuration Updated software routine in Section 5.4 Wake-up interrupt Minor textual updates

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